

#### INDIAN INSTITUTE OF SCIENCE EDUCATION AND RESEARCH TIRUPATI

#### CLARIFICATION ON TENDER NUMBER: IISERT/PUR/0992/20

#### ITEM DESCRIPTION-SUPPLY, INSTALLATION AND COMMISSIONING OF FE-SEM

REFER OUR TENDER NO: IISERT/PUR/0992/20 DATED 5-APRIL -2021 FOR SUPPLY, INSTALLATION AND COMMISSIONING OF FIELD EMISSION SCANNING ELECTRON MICROSCOPE (FE-SEM)

Pre-Bid meeting was held on April 12<sup>th</sup>, 2021 at 15:30 Via Google Meet and minutes of meeting is as under.

At the outset, the Chairman welcomed all the Members and the representative of the Prospective Bidders and briefed in general the scope of the Project and thereafter requested Assistant Registrar (S&P) to brief the vendors on the salient features of the commercial terms and the indenting Officer to read out the clarification sought by the Prospective Bidders and replied thereto as detailed in **Annexure -II** 

The representatives present were satisfied with the replies given and it was informed that the corrections / additions / clarifications given, as discussed during the Pre-Bid Conference would be hosted on the website of IISER Tirupati and all the Prospective Bidders are required to take cognizance of the proceedings of the Pre-Bid Conference before submitting their bids as stipulated in the Bidding Documents.

The other terms & conditions of the notice issued on our IISER website http://www.iisertirupati.ac.in/will remain unchanged. No more correspondence in this regard will be entertained

The meeting ended with vote of thanks to the Chair

20.4.2021

Sd/-Assistant Registrar (A&P)



# IISER TIRUPATI PRE-BID CONFERENCE FOR INSTALLATION AND COMMISSIONING OF FE-SEM

#### **TECHNICAL QUERIES AND CLARIFICATION**

DATE: 12/04/2021

### TENDER NUMBER - IISERT/PUR/0992/20

S.No	Point No	Query/Clarification Sought	Clarification / Amendment
1	23	EDS system	Modified with 40 mm <sup>2</sup> or better
		Detector area: 30 mm <sup>2</sup> or better has to be modified	Resolution: 127 eV or better resolution
		Resolution: 129 eV or better	
2	2	Resolution: 1nm@1kV In-Lens BSE and All resolution values to be achieved without any sample or stage biasing: Although both parameters are possible with JEOL FESEM, it is not mentioned in product brochure as they are not very important parameters from our factory viewpoint	No change
3	7	JEOL has maximum stage X=70mm, Y=50 mm & Z=40mm	No change
4	11	Beam Deceleration & Beam booster are different techniques.	No change
5	24	Future upgradation to Raman is possible but not mentioned in the brochure, reasons as stated in Point1.	No change in the specifications, but the supplier has to provide the supporting data for the pre-installation with Raman probe, preferably in India
6	4	Voltage Range as <50V or better to 30 kV, variable in 10 V steps	No change in the lower range



7	6	Chamber dimensions are as 300 mm or better inner diameter and 130 mm or better height.	Modified to 350 mm or better	
8	7	The sample stage must be 5-axis motorized, Eucentric/compucentric stage can be controlled by both computer and manually by joystick	No change in the Eucentric mode	
9	2	Resolution 0.5 nm or lower at 15 kV using Beam Deceleration.  0.8 nm or lower at 1 kV using Beam Deceleration.  0.7 nm or lower at 30kV STEM.  1.0 nm or lower at 1kV In-lens BSE using Beam Deceleration.	No change	
10	3	Magnification 29x- 1,200,000	No change	
11	6	Chamber inner dimension – 340 mm	Already modified to 350 mm or better	
12	7	Specimen size – 122 mm	No change	
13	16	Image pixel density – 6k x 4k	No change	



ANNEXURE -III

DATE: 12/04/2021

## IISER TIRUPATI PRE-BID CONFERENCE FOR INSTALLATION AND COMMISSIONING OF FE-SEM

### **COMMERCIAL QUERIES AND CLARIFICATION**

### TENDER NUMBER - IISERT/PUR/0992/20

Sr. No	Query/Clarification Sought	Clarification / Amendment
	NIL	NIL